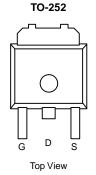
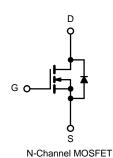


N-Channel 80 V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	R _{DS(on)} (Ω) Max.	I _D (A)	Q _g (Typ.)			
	0.0055 at V _{GS} = 10 V	75 ^a				
80	0.0088 at V _{GS} = 6.0 V	65 ^a	17.1 nC			
	0.0115 at V _{GS} = 5.0 V	54				





FEATURES

- TrenchFET® Power MOSFET
- 100 % R_g and UIS Tested

COMPLIANT HALOGEN **FREE**

APPLICATIONS

- Primary Side Switching
- Synchronous Rectification
- DC/AC Inverters
- LED Backlighting

Parameter	Symbol	Limit	Unit		
Drain-Source Voltage	V _{DS}	80	.,		
Gate-Source Voltage		V_{GS}	± 20	V	
	T _C = 25 °C		75 ^a		
Continuous Dunis Comment /T 150 °C	T _C = 70 °C		62.7		
Continuous Drain Current (T _J = 150 °C)	T _A = 25 °C	I _D	28.6 ^{b, c}		
	T _A = 70 °C		24.9 ^{b, c}		
Pulsed Drain Current (t = 100 μs)		I _{DM}	150	A	
Continuous Courses Drain Diada Current	T _C = 25 °C		75a		
Continuous Source-Drain Diode Current	T _A = 25 °C	l _s —	4.5 ^{b, c}		
Single Pulse Avalanche Current	l 0.1 mll	I _{AS}	30		
Single Pulse Avalanche Energy L = 0.1 m		E _{AS}	45	mJ	
	T _C = 25 °C		62.5		
Manian and David Dispiration	T _C = 70 °C		40	14/	
Maximum Power Dissipation	T _A = 25 °C	P _D	5 ^{b, c}	W	
	T _A = 70 °C		3.2 ^{b, c}		
Operating Junction and Storage Temperature R	T _J , T _{stg}	- 55 to 150	°C		
Soldering Recommendations (Peak Temperatur		260			

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{b, f}	t ≤ 10 s	R_{thJA}	20	25	°C ///	
Maximum Junction-to-Case (Drain)	Steady State	R _{thJC}	1.5	2.0	°C/W	

Notes

- a. Package limited.
- b. Surface mounted on 1" x 1" FR4 board.
- d. The TO-220 is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.
- e. Rework conditions: manual soldering with a soldering iron is not recommended for leadless components.
- f. Maximum under steady state conditions is 70 °C/W.



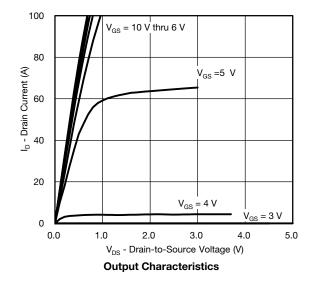
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static				<u> </u>		1	
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	80			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$			37		1400	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA		- 6.1		mV/°C	
Gate-Source Threshold Voltage	V _{GS(th})	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2.5		4.0	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zana Oala Vallana Baria Oanad		$V_{DS} = 80 \text{ V}, V_{GS} = 0 \text{ V}$			1	_	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 80 V, V _{GS} = 0 V, T _J = 55 °C			10	μΑ	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	30			Α	
	. ,	$V_{GS} = 10 \text{ V}, I_D = 20 \text{ A}$		0.0050	1		
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = 6 V, I _D = 15 A		0.0070		Ω	
		$V_{GS} = 5.0 \text{ V}, I_D = 10 \text{ A}$		0.0087			
Forward Transconductance ^a	9 _{fs}	$V_{DS} = 10 \text{ V}, I_D = 20 \text{ A}$		60		S	
Dynamic ^b				•		•	
Input Capacitance	C _{iss}			1855		pF	
Output Capacitance	C _{oss}	$V_{DS} = 40 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		950			
Reverse Transfer Capacitance	C _{rss}			76		1	
		$V_{DS} = 40 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 10 \text{ A}$		35.5	54	nC	
Total Gate Charge	Qg	V _{DS} = 40 V, V _{GS} = 6 V, I _D = 10 A		22	33		
				17.1	26		
Gate-Source Charge	Q_{gs}	$V_{DS} = 40 \text{ V}, V_{GS} = 4.5 \text{ V}, I_D = 10 \text{ A}$		5.3			
Gate-Drain Charge	Q_{gd}			7.3			
Output Charge	Q _{oss}	V _{DS} = 40 V, V _{GS} = 0 V		57	86		
Gate Resistance	R_{g}	f = 1 MHz	0.5	1.3	2	Ω	
Turn-On Delay Time	t _{d(on)}			12	24		
Rise Time	t _r	$V_{DD} = 40 \text{ V}, R_L = 4 \Omega$		8	16		
Turn-Off DelayTime	t _{d(off)}	$I_D \cong 10 \text{ Å}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		32	64	- ns	
Fall Time	t _f			7	14		
Turn-On Delay Time	t _{d(on)}			14	28		
Rise Time	t _r			11	22		
Turn-Off DelayTime	t _{d(off)}	$I_D \cong 10 \text{ A}, V_{GEN} = 6.0 \text{ V}, R_g = 1 \Omega$		30	60		
Fall Time	t _f			8	16		
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			75	А	
Pulse Diode Forward Current (t = 100 μs)	I _{SM}				150	^	
Body Diode Voltage	V_{SD}	I _S = 5 A		0.76	1.1	V	
Body Diode Reverse Recovery Time	t _{rr}			38	75	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	I= = 10 A dl/dt = 100 A/vo T: = 25 °C		36	70	nC	
Reverse Recovery Fall Time	ta	$I_F = 10 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 °\text{C}$		19		200	
Reverse Recovery Rise Time	t _b			19		ns	

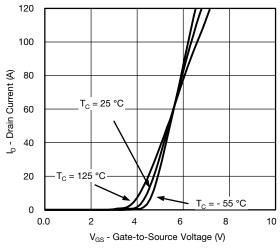
Notes

- a. Pulse test; pulse width $\leq 300~\mu s,~duty~cycle \leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

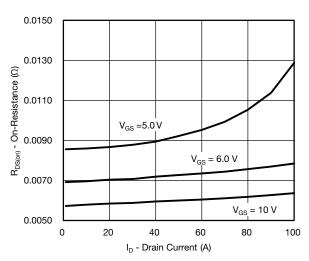
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

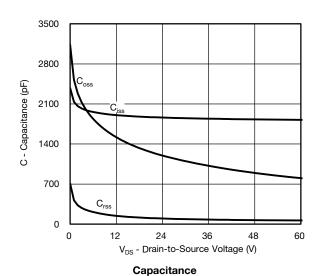




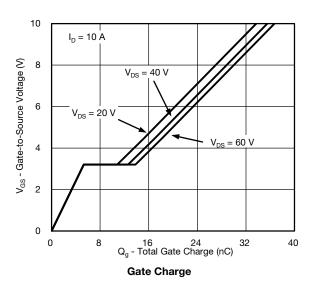


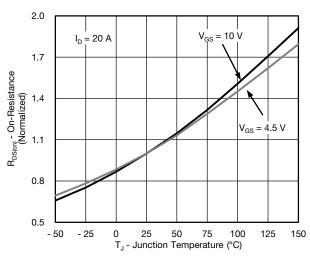
Transfer Characteristics





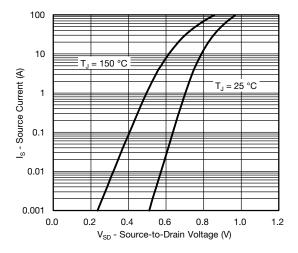
On-Resistance vs. Drain Current



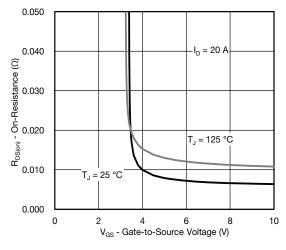


On-Resistance vs. Junction Temperature

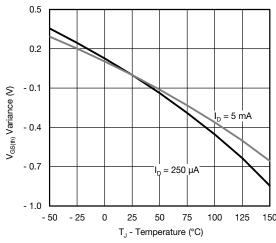




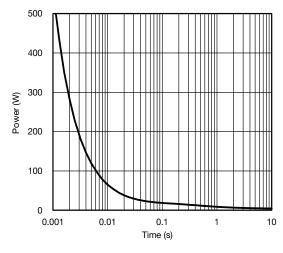
Source-Drain Diode Forward Voltage



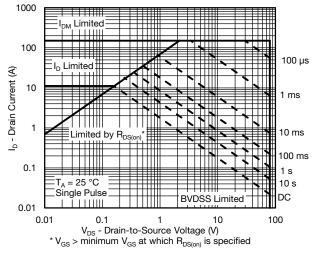
On-Resistance vs. Gate-to-Source Voltage



Threshold Voltage

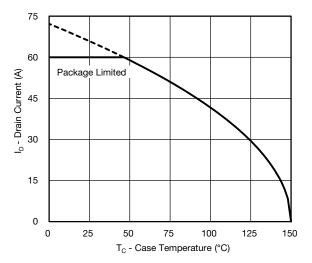


Single Pulse Power, Junction-to-Ambient

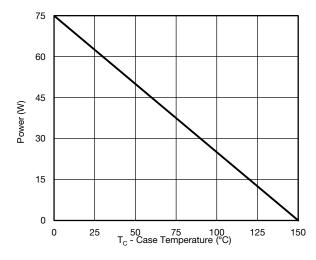


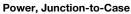
Safe Operating Area, Junction-to-Ambient

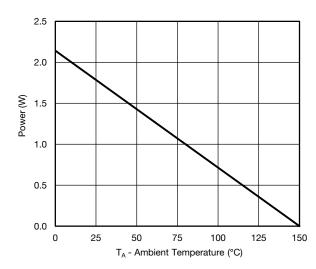




Current Derating*



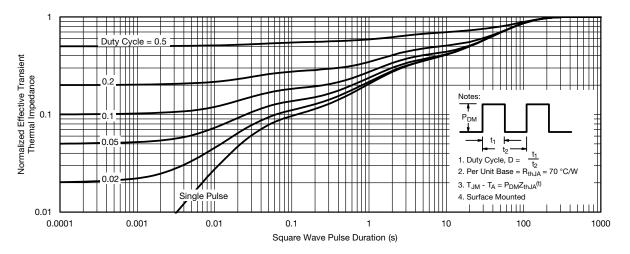




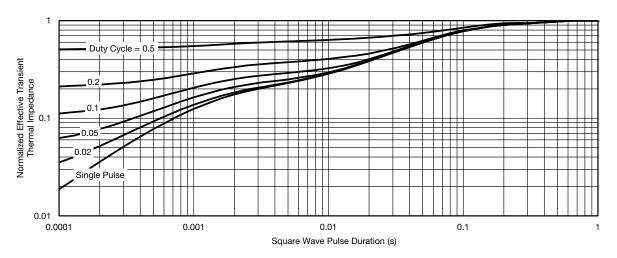
Power, Junction-to-Ambient

^{*} The power dissipation P_D is based on $T_{J(max.)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





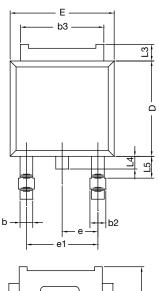
Normalized Thermal Transient Impedance, Junction-to-Ambient

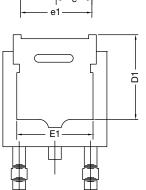


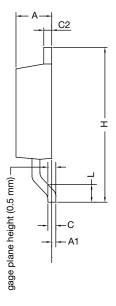
Normalized Thermal Transient Impedance, Junction-to-Case



TO-252AA CASE OUTLINE







	MILLIMETERS		INC	HES	
DIM.	MIN.	MAX.	MIN.	MAX.	
Α	2.18	2.38	0.086	0.094	
A1	-	0.127	-	0.005	
b	0.64	0.88	0.025	0.035	
b2	0.76	1.14	0.030	0.045	
b3	4.95	5.46	0.195	0.215	
С	0.46	0.61	0.018	0.024	
C2	0.46	0.89	0.018	0.035	
D	5.97	6.22	0.235	0.245	
D1	5.21	-	0.205	-	
E	6.35	6.73	0.250	0.265	
E1	4.32	-	0.170	-	
Н	9.40	10.41	0.370	0.410	
е	2.28 BSC		0.090 BSC		
e1	4.56 BSC		0.180 BSC		
L	1.40	1.78	0.055	0.070	
L3	0.89	1.27	0.035	0.050	
L4	-	1.02	-	0.040	
L5	1.14	1.52	0.045	0.060	
ECN: X12-0247-Rev. M, 24-Dec-12					

ECN: X12-0247-Rev. M, 24-Dec-1 DWG: 5347

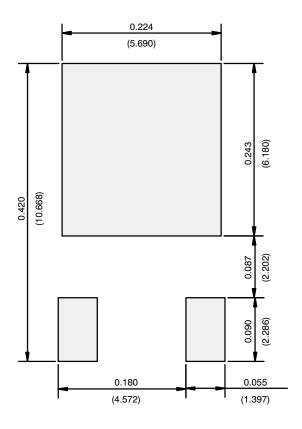
Note

• Dimension L3 is for reference only.

7



RECOMMENDED MINIMUM PADS FOR DPAK (TO-252)



Recommended Minimum Pads Dimensions in Inches/(mm)

WWW. Doomingon

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